

**Search Notes**

Application/Control No.

10/633,243

Examiner,

Alan S. Chen

Applicant(s)/Patent under  
Reexamination

BABKA ET AL.

Art Unit

2182

**SEARCHED**

Class	Subclass	Date	Examiner
710	15-19	8/4/2006	ASC
↓	52-57	↓	↓
↓	104	↓	↓
713	1	↓	↓
↓	2	↓	↓
↓	100	↓	↓

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
(EAST) USPAT; USPGPUB; EPO; JPO; IBM_TDB; DERWENT PLUS; Inventor Search; limited class search	8/4/2006	ASC
101 Help Panel	8/4/2006	ASC